


Methods, FMF, Fiederle

<p style="text-align: center;">CoReMa</p> <p style="text-align: center;"><i>Contactless Resistivity Mapping</i></p>	<p>Model: <i>FMF model</i> Unit and Room: <i>FMF, 3rd floor, R. 03005</i> Responsible: <i>Dr. M. Fiederle, 203 4775</i> Further information: <i>www.fmf.uni-freiburg.de/service/servicegruppen/sg_matchar/chat/</i></p>	
<p>Short Description:</p> <p>Contactless measurement of resistivity of solid state materials. Spatial mapping with 0.5 mm resolution and temperature controlling.</p>	<p style="text-align: center;">Picture of the Equipment</p> 	
<p>Available Experiments/Techniques:</p> <ul style="list-style-type: none"> - Mappings of resistivity for samples up to 100 mm diameter - Measurements of resistivities from 10^5 Ohmcm up to 10^{12} Ohmcm 		
<p>Special Equipment:</p> <p>Temperature controlling (270 K up to 350 K) Use of LEDs with different wave lengths for Surface Photo Voltage measurements</p>		
<p>Measurements on the equipment are currently done by:</p>	<p><input type="checkbox"/> Students <input type="checkbox"/> Students after Introduction <input checked="" type="checkbox"/> Students after extensive training <input checked="" type="checkbox"/> Trained scientific service personal</p>	
<p>Recent Publications, where this instrument was important (optional): Give citation</p>	<p>V Babentsov, J Franc, A Fauler, M Fiederle, R B James (2008) Distribution of zinc, resistivity, and photosensitivity in a vertical Bridgman grown $Cd_{1-x}Zn_xTe$ ingot JOURNAL OF CRYSTAL GROWTH 310: 15. 3482-3487</p>	
<p>Typical problems that may be solved with this instrument:</p>	<ul style="list-style-type: none"> - <i>Investigations of resistivity distribution-</i> - <i>Identification of inhomogeneities</i> - <i>Identification of impurities and defects</i> 	